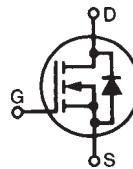


**HiPerFET™ Power
MOSFET
ISOPLUS247™**

(Electrically Isolated Back Surface)

IXFR24N100



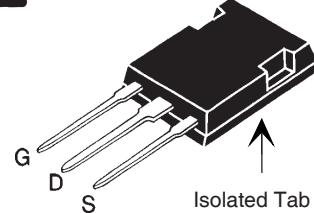
V_{DSS} = 1000V
 I_{D25} = 22A
 $R_{DS(on)}$ ≤ 390mΩ
 t_{rr} ≤ 250ns

N-Channel Enhancement Mode
Avalanche Rated

Symbol	Test Conditions	Maximum Ratings		
V_{DSS}	$T_J = 25^\circ\text{C}$ to 150°C	1000		V
V_{DGR}	$T_J = 25^\circ\text{C}$ to 150°C , $R_{GS} = 1\text{M}\Omega$	1000		V
V_{GSS}	Continuous	±20		V
V_{GSM}	Transient	±30		V
I_{D25}	$T_c = 25^\circ\text{C}$	22		A
I_{DM}	$T_c = 25^\circ\text{C}$, pulse width limited by T_{JM}	96		A
I_A	$T_c = 25^\circ\text{C}$	24		A
E_{AS}	$T_c = 25^\circ\text{C}$	3		J
dV/dt	$I_s \leq I_{DM}$, $V_{DD} \leq V_{DSS}$, $T_J \leq 150^\circ\text{C}$	5	V/ns	
P_D	$T_c = 25^\circ\text{C}$	416		W
T_J		-55 ... +150		°C
T_{JM}		150		°C
T_{stg}		-55 ... +150		°C
T_L	1.6mm (0.062 in.) from case for 10s	300		°C
T_{SOLD}	Plastic body for 10s	260		°C
V_{ISOL}	50/60 Hz, RMS	t = 1min	2500	V~
	$I_{ISOL} \leq 1\text{mA}$	t = 1s	3000	V~
M_d	Mounting force	20..120 / 4.5..27		N/lb.
Weight		5		g

Symbol	Test Conditions ($T_J = 25^\circ\text{C}$, unless otherwise specified)	Characteristic Values		
		Min.	Typ.	Max.
BV_{DSS}	$V_{GS} = 0\text{V}$, $I_D = 3\text{mA}$	1000		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 8\text{mA}$	3.0		V
I_{GSS}	$V_{GS} = \pm 20\text{V}$, $V_{DS} = 0\text{V}$			$\pm 200\text{ nA}$
I_{DSS}	$V_{DS} = V_{DSS}$ $V_{GS} = 0\text{V}$			$100\text{ }\mu\text{A}$ 2 mA
$R_{DS(on)}$	$V_{GS} = 10\text{V}$, $I_D = 12\text{A}$, Note 1			390 mΩ

ISOPLUS247



G = Gate D = Drain
S = Source

Features

- Silicon chip on Direct-Copper-Bond substrate
 - High power dissipation
 - Isolated mounting surface
 - 2500V electrical isolation
- Low drain to tab capacitance(<30pF)
- Low $R_{DS(on)}$ HDMOS™ process
- Rugged polysilicon gate cell structure
- Avalanche rated
- Fast intrinsic Rectifier

Applications

- DC-DC converters
- Battery chargers
- Switched-mode and resonant-mode power supplies
- DC choppers
- AC motor drives

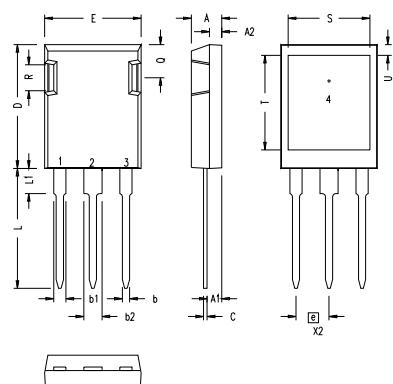
Advantages

- Easy assembly
- Space savings
- High power density

Symbol	Test Conditions ($T_J = 25^\circ\text{C}$, unless otherwise specified)		Characteristic Values		
			Min.	Typ.	Max.
g_{fs}	$V_{DS} = 10\text{V}$, $I_D = 12\text{A}$, Note 1	15	27	S	
C_{iss}		8700		pF	
C_{oss}	$V_{GS} = 0\text{V}$, $V_{DS} = 25\text{V}$, $f = 1\text{MHz}$	785		pF	
C_{rss}		315		pF	
$t_{d(on)}$		35		ns	
t_r		35		ns	
$t_{d(off)}$	$V_{GS} = 10\text{V}$, $V_{DS} = 0.5 \cdot V_{DSS}$, $I_D = 12\text{A}$	75		ns	
t_f	$R_G = 1\Omega$ (External)	21		ns	
$Q_{g(on)}$		267		nC	
Q_{gs}	$V_{GS} = 10\text{V}$, $V_{DS} = 0.5 \cdot V_{DSS}$, $I_D = 12\text{A}$	52		nC	
Q_{gd}		142		nC	
R_{thJC}			0.30	$^\circ\text{C}/\text{W}$	
R_{thCS}		0.15		$^\circ\text{C}/\text{W}$	

Source-Drain Diode

Symbol	Test Conditions ($T_J = 25^\circ\text{C}$, unless otherwise specified)		Characteristic Values		
			Min.	Typ.	Max.
I_s	$V_{GS} = 0\text{V}$			24	A
I_{SM}	Repetitive, pulse width limited by T_{JM}			96	A
V_{SD}	$I_F = 24\text{A}$, $V_{GS} = 0\text{V}$, Note 1			1.5	V
t_{rr}	$I_F = 24\text{A}$, $-di/dt = 100\text{A}/\mu\text{s}$			250	ns
Q_{RM}		1.0			μC
I_{RM}	$V_R = 100\text{V}$, $V_{GS} = 0\text{V}$	8.0			A

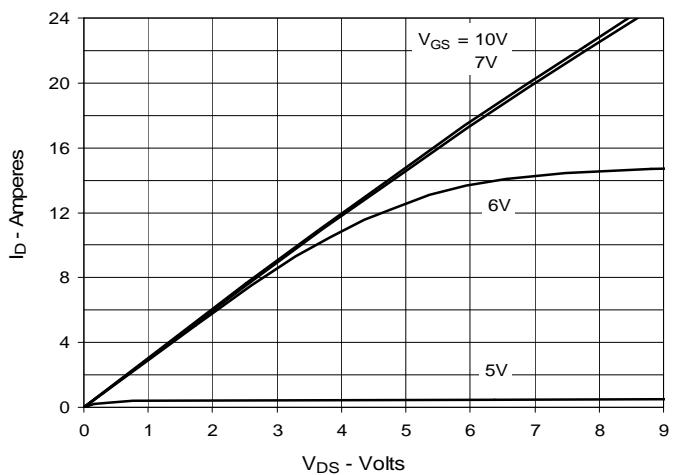
Note 1: Pulse test, $t \leq 300\mu\text{s}$; duty cycle, $d \leq 2\%$.**ISOPLUS247 (IXFR) Outline**

SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.190	.205	4.83	5.21
A1	.090	.100	2.29	2.54
A2	.075	.085	1.91	2.16
b	.045	.055	1.14	1.40
b1	.075	.084	1.91	2.13
b2	.115	.123	2.92	3.12
C	.024	.031	0.61	0.80
D	.819	.840	20.80	21.34
E	.620	.635	15.75	16.13
e	.215 BSC		5.45 BSC	
L	.780	.800	19.81	20.32
L1	.150	.170	3.81	4.32
Q	.220	.244	5.59	6.20
R	.170	.190	4.32	4.83
S	.520	.540	13.21	13.72
T	.620	.640	15.75	16.26
U	.065	.080	1.65	2.03

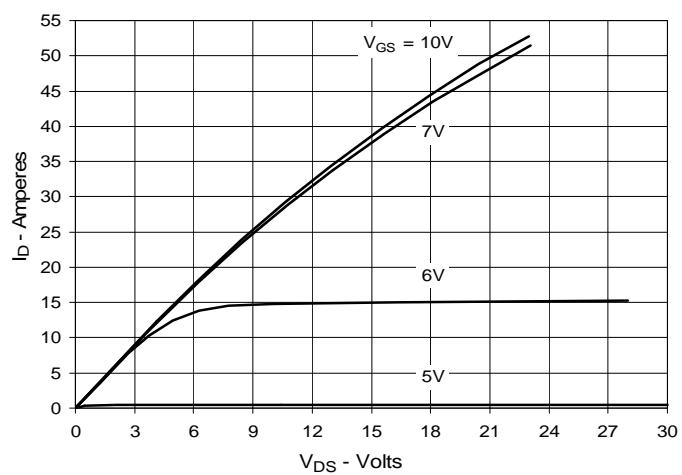
1 - GATE
2 - DRAIN (COLLECTOR)
3 - SOURCE (EMITTER)
4 - NO CONNECTION

NOTE: This drawing will meet all dimensions requirement of JEDEC outline TO-247AD except screw hole.

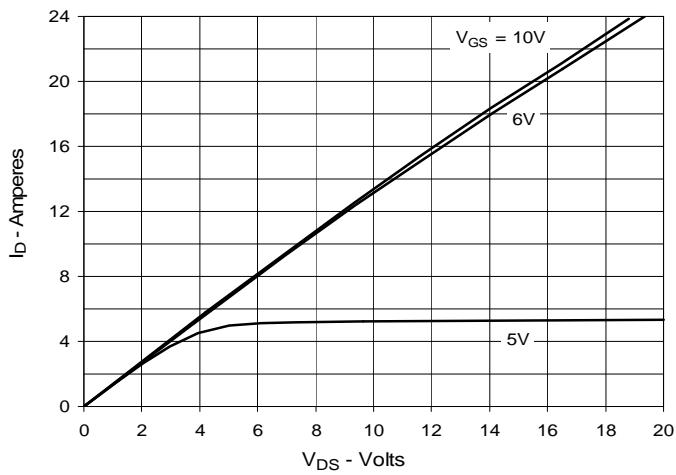
**Fig. 1. Output Characteristics
@ 25°C**



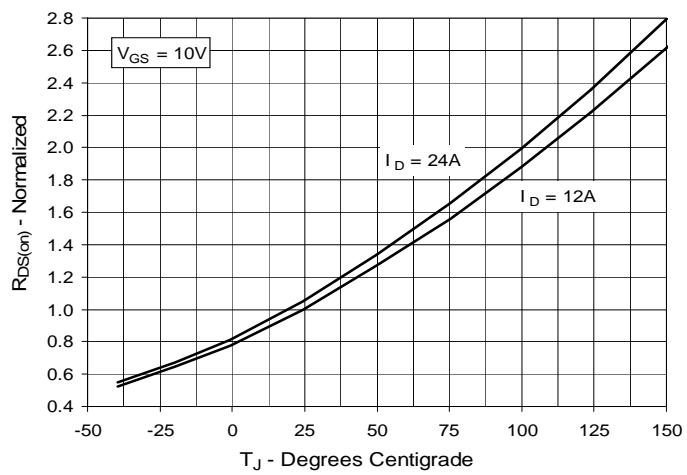
**Fig. 2. Extended Output Characteristics
@ 25°C**



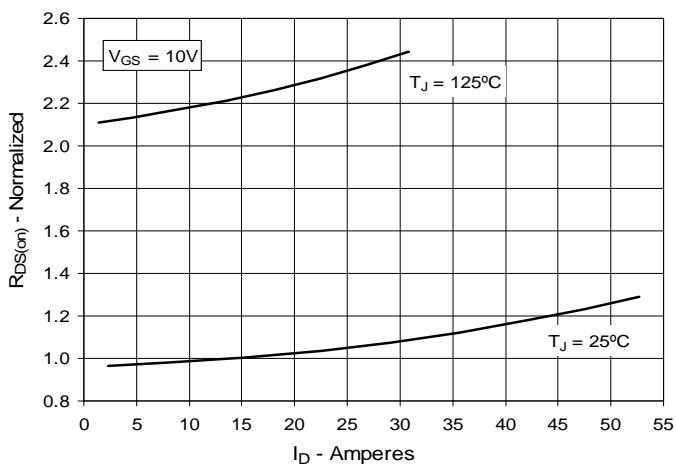
**Fig. 3. Output Characteristics
@ 125°C**



**Fig. 4. $R_{DS(on)}$ Normalized to $I_D = 12A$ Value
vs. Junction Temperature**



**Fig. 5. $R_{DS(on)}$ Normalized to $I_D = 12A$ Value
vs. Drain Current**



**Fig. 6. Maximum Drain Current vs.
Case Temperature**

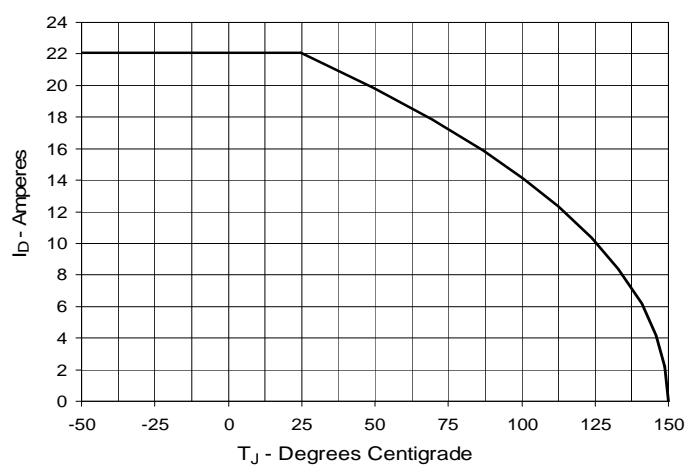
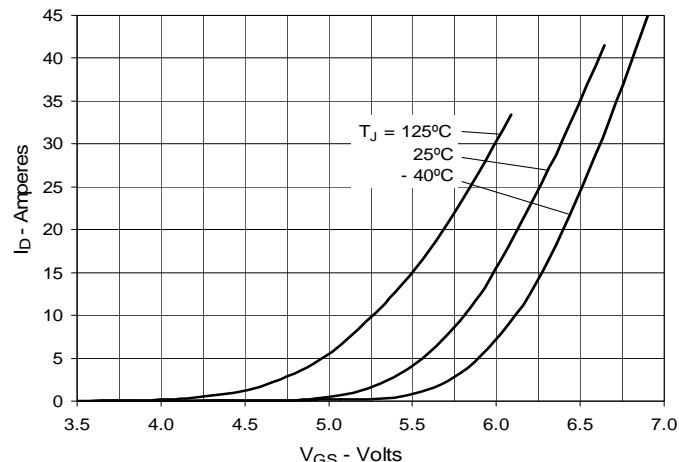
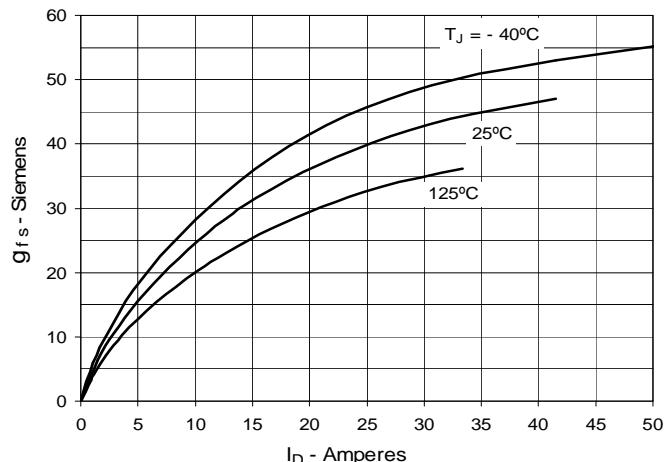
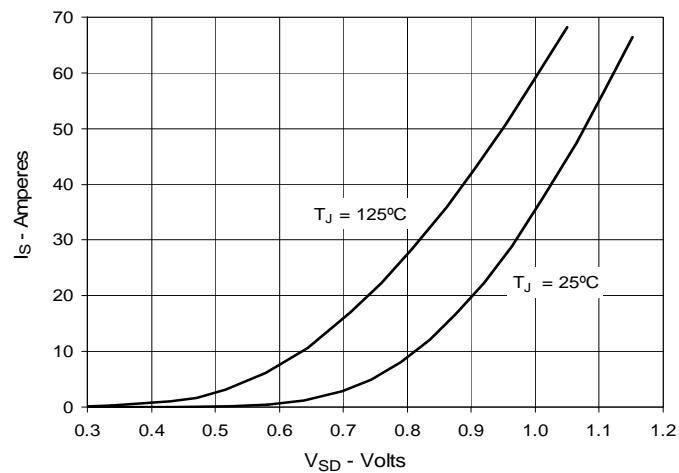
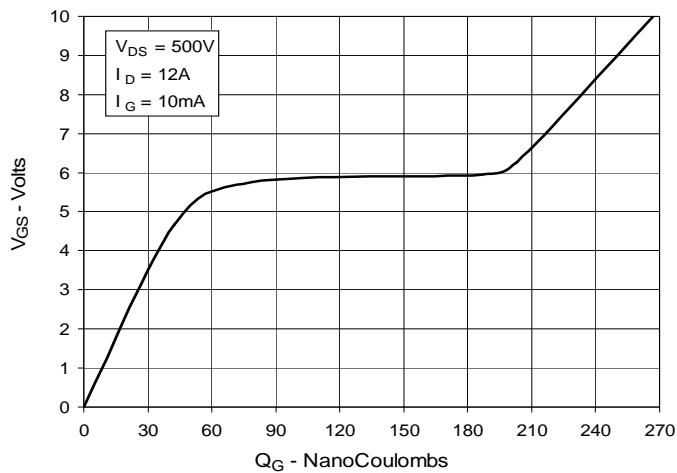
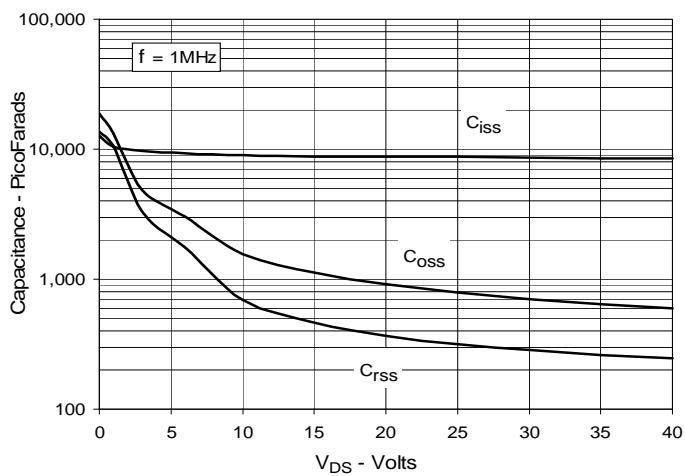
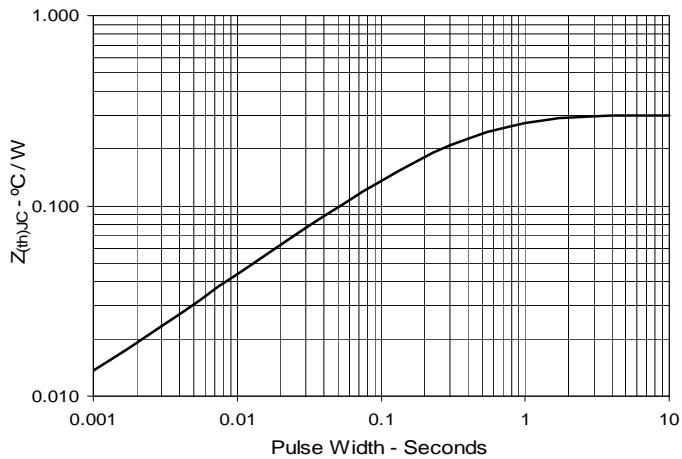


Fig. 7. Input Admittance**Fig. 8. Transconductance****Fig. 9. Forward Voltage Drop of Intrinsic Diode****Fig. 10. Gate Charge****Fig. 11. Capacitance****Fig. 12. Maximum Transient Thermal Impedance**

IXYS reserves the right to change limits, test conditions, and dimensions.